

Combinatorial Testing in Japan

- History, applications, techniques and tools -

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Outline

- ⊙ **Prevailing view to the history of CT**
- ⊙ **The actual history**
- ⊙ **Prehistory**
 - ❖ The early history of Fujitsu's mainframe computers
 - ❖ Test case design process in Fujitsu
- ⊙ **The birth of CT**
 - ❖ Application of Design of Experiments
 - ❖ Test case design support system
- ⊙ **Transferred CT technique to US**
- ⊙ **Genealogy of combinatorial testing**
- ⊙ **Current status of CT in Japan**
 - ❖ HAYST method
 - ❖ PictMaster
- ⊙ **Concluding remarks**

Prevailing view to the history of CT

Mandl's paper is the first ??

The screenshot shows a web browser window with the URL www.pairwise.org/default.html. The page title is "Pairwise Testing" and the subtitle is "Combinatorial Test Case Generation". The main text describes pairwise testing as an effective test case generation technique based on the observation that most faults are caused by interactions of at most two factors. It states that pairwise-generated test suites are much smaller than exhaustive ones and are good at finding defects.

Below the text, there is a section titled $L_4 (2^3)$ Orthogonal Array, which contains a table:

Expt. No.	Column 1	Column 2	Column 3
1	1	1	1
2	1	2	2
3	2	1	2
4	2	2	1

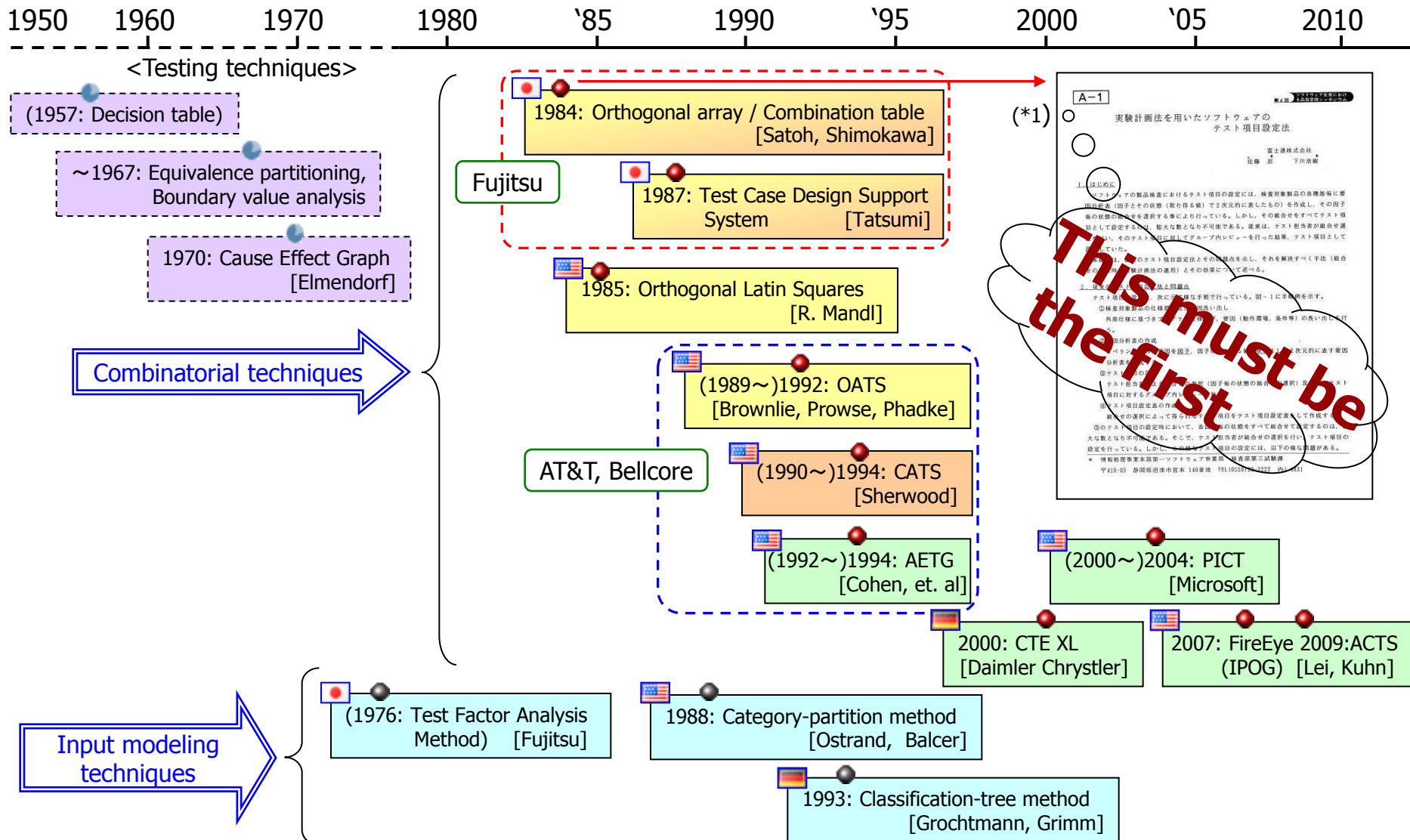
On the right side of the page, there is a sidebar with a list of links: "What's New", "Effectiveness of", "Research Papers", "Articles and Other", "Available Tools", and "About this Website". Below these links, there is a section titled "Research Papers" with a list of three papers:

1. R. Mandl, *Orthogonal Communication*
2. K. Tatsumi, *Conceptual Test Case Proc. 11th*
3. K. Tatsumi, *Test Case Proceeding*

At the bottom of the page, it says "Maintained by Jacek Czerwinka Last updated: Jul 2004".

1. R. Mandl
Orthogonal Latin squares: an application of experiment design to compiler testing
Communications of the ACM, v.28 n.10, p.1054-1058, Oct. 1985
2. K. Tatsumi, S. Watanabe, Y. Takeuchi, H. Shimokawa
Conceptual support for test case design
Proc. 11th Intl. Computer Software and Applications Conf. (COMPSAC), October 1987,
3. K. Tatsumi
Test Case Design Support System
Proceedings of International Conference on Quality Control (ICQC), Tokyo, 1987, pp. 6.
4. R. Brownlie, J. Prowse, and M.S. Phadke
Robust Testing of AT&T PMX/StarMAIL using OATS
AT&T Technical Journal, May/June 1992, pp. 41-47
5. K. Burroughs, A. Jain, and R. L. Erickson
Improved quality of protocol testing through techniques of experimental design
In Proceedings of the IEEE International Conference on Communications (Supercomm/ICC'94), May 1-5, New Orleans, Louisiana, USA. IEEE, May 1994, pp. 745-752
6. D. M. Cohen, S. R. Dalal, J. Parelius, G. C. Patton
The Combinatorial Design Approach to Automatic Test Generation
IEEE Software, Vol. 13, No. 5, pp. 83-87, September 1996
7. A.W. Williams, R.L. Probert
A practical strategy for testing pair-wise coverage of network interfaces
The Seventh International Symposium on Software Reliability Engineering (ISSRE '96) p. 246

The actual history

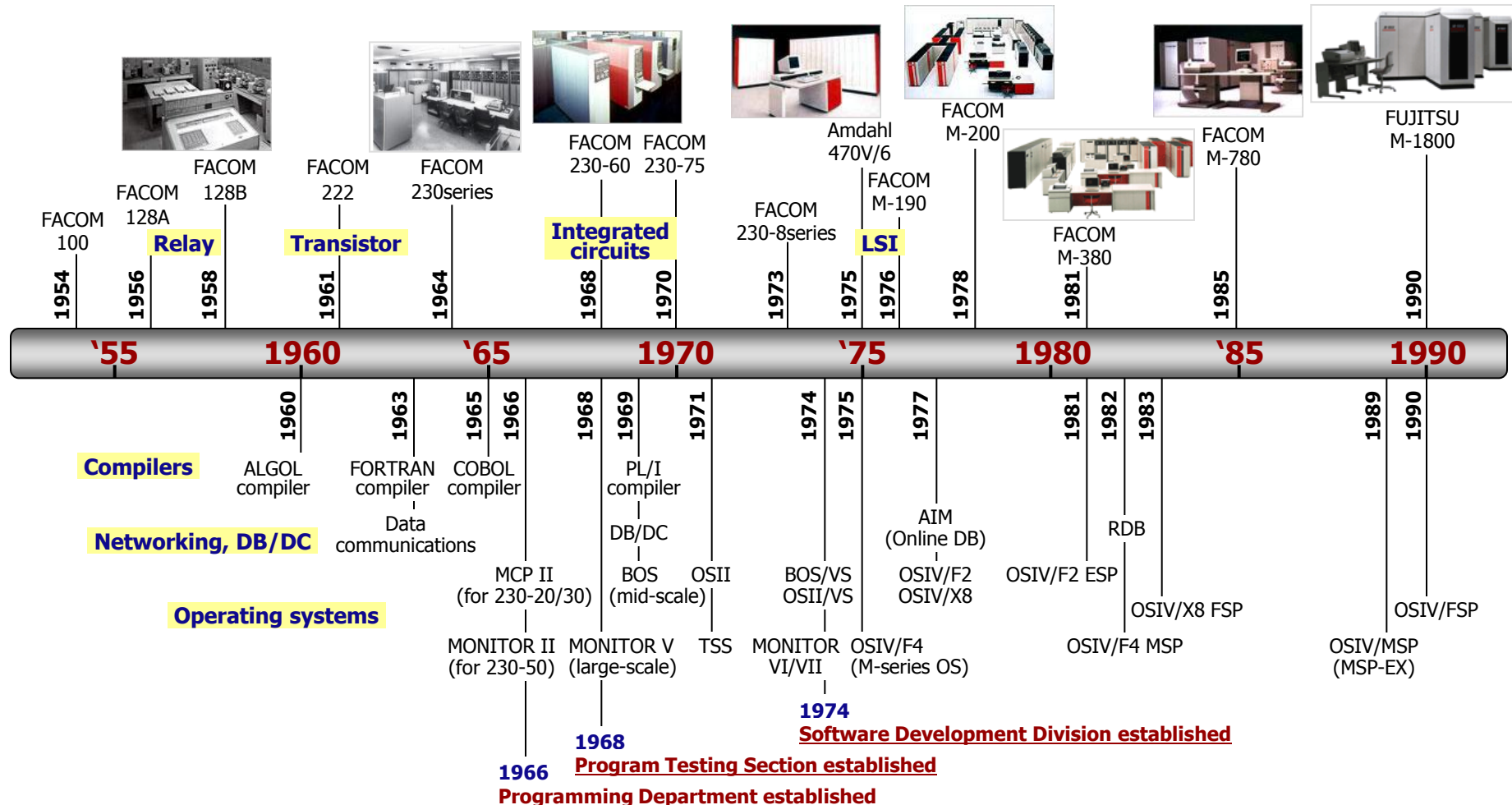


(*1) S. Sato and H. Shimokawa, Methods for setting software test parameters using the design of experiments method (in Japanese), in Proceedings of 4th Symposium on Quality Control in Software, Union of Japanese Scientists and Engineers (JUSE), 1984, pp. 1-8.

(c) K. Tatsumi 2013

Prehistory

◎ The early history of Fujitsu's mainframe computers



M. A. Cusumano, "Japan's Software Factories: A Challenge to U.S. Management," Oxford University Press, 1991
 K. Tatsumi, The History of Software Engineering and Software Testing - World and Japan -

<http://a-lifelong-tester.cocolog-nifty.com/Chronology/ChronologyEng.html>

Prehistory

◎ Test case design process in Fujitsu

(From early 1970s)

Step1. Test Classification

- Functions are divided into smaller units.

Step2. Test Factor Analysis

- Input conditions and environmental conditions (*Factors*) and their values (*States*) are identified from external specifications.

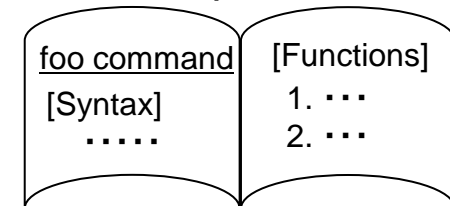
Step3. Test Case Generation

- Test cases are generated by combining the states of the factors.

Step4. Definition of Test Results

- Expected results are defined for each generated test cases.

<External specifications>



<Test factor table>

Factors		A	B	C	D
States	1	a1	b1	c1	d1
	2	a2	b2	c2	d2
	3	a3		c3	d3
	4			c4	



<Test case table>

Factors	A	B	C	D
Test case 1	a1	b1	c1	d1
Test case 2	a2	b2	c3	d2
Test case n	a3	b1	c4	d3

(c) K. Tatsumi 2013

Application of Design of Experiments

From Tatsumi's COMPSAC'87 presentation slides

STANDARD OF TEST CASE GENERATION

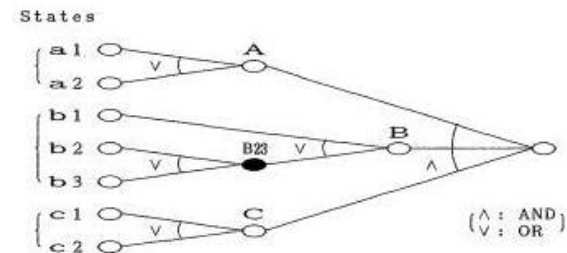
- **ORTHOGONAL ARRAY** (The Design of Experiments)
The same number of combination of states between any two factors.

Factor Test case	1	2	3	4	5	6	7	8	9...
T1	1	1	1	1	1	1	1	1	1
T2	2	1	2	1	1	2	2	1	2
T3	1	2	2	1	2	1	2	1	1
T4	2	2	1	1	2	2	1	1	2
T5	1	1	1	2	2	2	2	1	1
T6	2	1	2	2	2	1	1	1	2
T7	1	2	2	2	1	2	1	1	1
T8	2	2	1	2	1	1	2	1	2
T9	1	1	1	1	1	1	1	2	2

- **COMBINATION TABLE**
At least one combination of states between any two factors.

Factor Test case	1	2	3	4	5	6	7	8	9...
T1	1	1	1	1	1	1	1	1	1
T2	2	1	2	2	1	2	2	1	2
T3	1	2	2	1	2	2	1	2	2
T4	2	2	1	2	2	1	2	2	1
T5	1	1	2	2	2	1	1	1	2
T6	2	2	1	1	1	2	2	2	1
T7	1	2	2	2	1	2	2	1	1
T8	2	1	1	1	2	1	1	2	2
T9	1	2	1	1	2	1	2	2	1

APPLICATION OF THE COMBINATION TABLE



(Test factor table)

A	B	C
1	a1	b1
2	a2	b2
3		b3

Standardized into two states

Combination table applied (3 factors)

	1	2	3
T1	1	1	1
T2	2	1	2
T3	1	2	2
T4	2	2	1

(Test case table)

A	B	C
T1	a1	b1
T2	a2	b1
T3	a1	b2
T4	a2	b2
T5	a2	b3
T6	a2	b3

Combination table applied (1 factor) to each B23

	1
T1	1
T2	2

- Constraints handling like Cause-Effect Graph
- Exclusive
 - Inclusive
 - One and only one

The birth of CT (1986-1987)

◎ Test case design support system

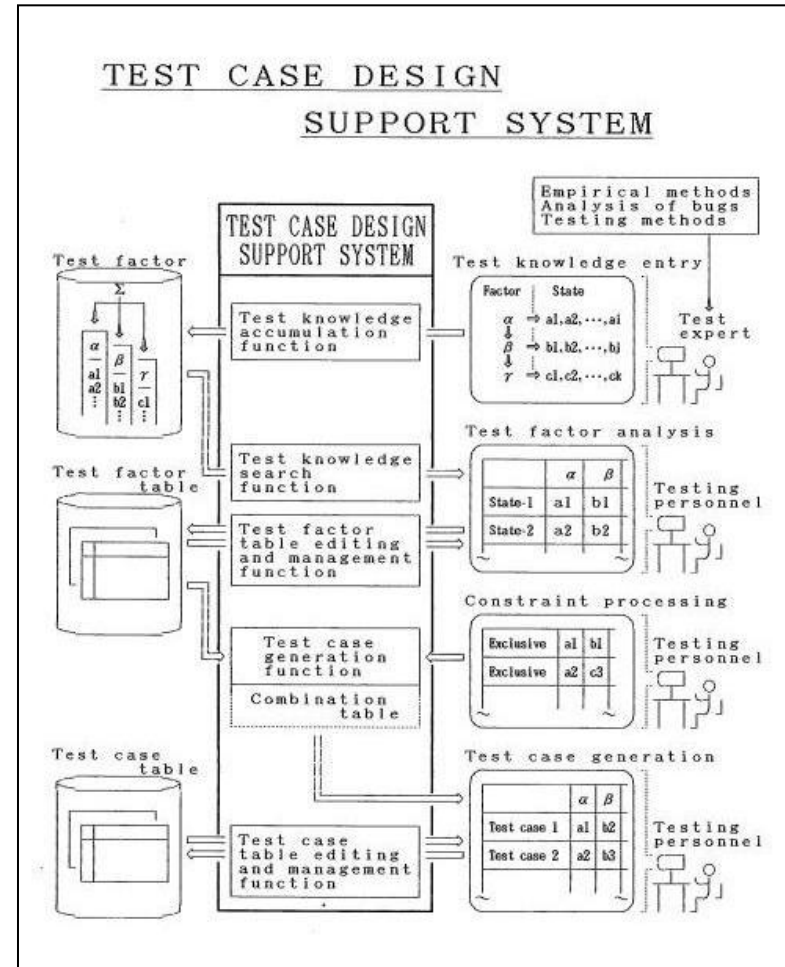
❖ Whole process support

- From test classification to test case generation
- Test documentation and revision management

❖ Refinement

- Generation algorithm
- Constraints handling
 - Between state-state, factor-state, factor-factor
 - » Exclusive combination
 - » No combination
 - » Required combination
 - » Grouping of states

From Tatsumi's COMPSAC'87 presentation slides



Transferred CT technique to US

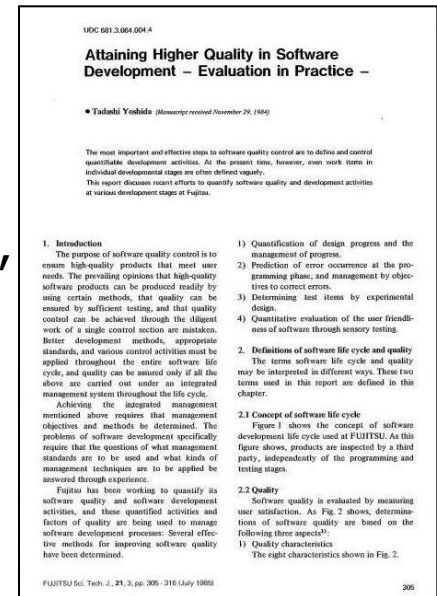
◎ Publications in English

- ❖ T. Yoshida, "Attaining Higher Quality in Software Development - Evaluation in Practice", FSTJ, 1985
- ❖ K. Tatsumi, "Conceptual Support for Test Case Design", COMPSAC'87
- ❖ K. Tatsumi, "Test Case Design Support System", ICQC'87

◎ Introducing to AT&T in 1989

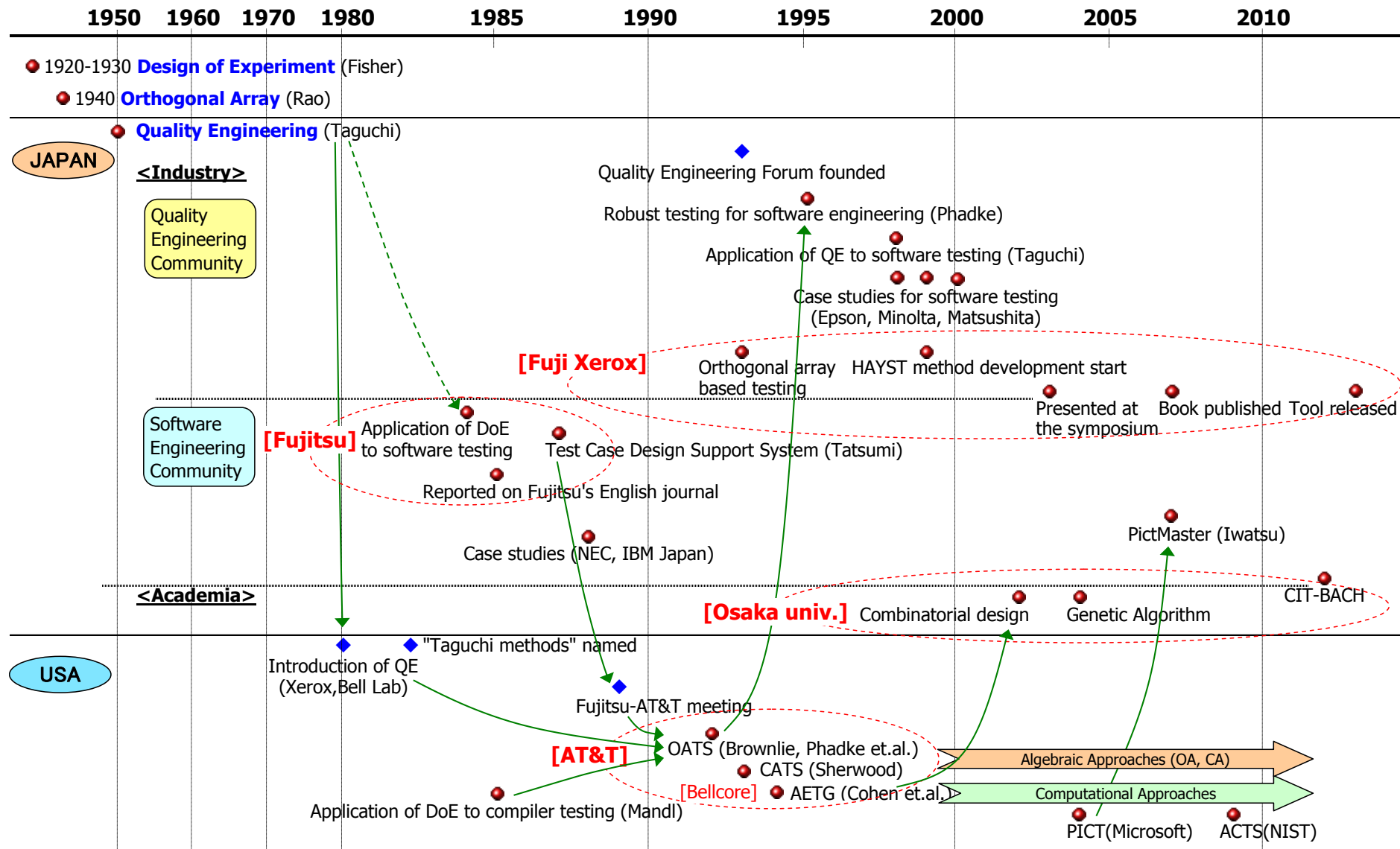
(According to Yoshida's book)

- ❖ Yoshida was requested for explanation about application of DoE from some AT&T engineer who had read his FSTJ paper.
- ❖ He and colleagues had a meeting with AT&T engineers and explained the technique at Marriott hotel in Somerset, N. J. on 30th April in 1989. It was while his travelling as a member of the 1st Software Production Quality Control Study Team of JUSE.
- ❖ Tatsumi's ICQC paper was the one of documents for explanation.



T. Yoshida, "Attaining Higher Quality in Software Development - Evaluation in Practice -", Fujitsu Scientific and Technical Journal, Vol.21, pp.305-316, 1985
T. Yoshida, "Technology transmission and transfer (in Japanese)", pp.113-114, JUSE press, 1994

Genealogy of combinatorial testing



Current status of CT in Japan (1/2)

◎ **Software testing community**

❖ **ASTER**: Association of Software Test EngineerRing

- Non profit organization for promoting software testing
- Operated / Managed by volunteers of software testing experts
- Activities
 - **Conference** - JaSST: Japan Symposium on Software Testing
 - **Certification** - JSTQB: Japan Software Testing Qualifications Board, member of ISTQB
 - **International collaboration** - ASTA (Asian Alliance) / ISO-IEC (International Std.)
 - **Education** - Seminars / Open materials / Univ. Curriculum / Test.SSF (Skills Standard)
 - **Research** - Research groups on Test Architecture and on Bug Analysis

Current status of CT in Japan (2/2)

◎ **Number of papers and presentations on CT**

1984-'90: **9**, '91-'95: **0**, '96-'00: **6**, '01-'05: **9**, '06- : **31**

◎ **Applications of CT**

(Questionnaire survey to the software testing experts of 5 major IT vendors)

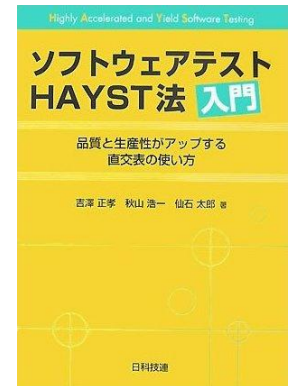
- ❖ CT has already been applied in all the vendors
- ❖ Tools
 - PICT, PictMaster, ACTS, HAYST, In-house tools
- ❖ Issues
 - Test design phase before combination is essential
 - Selection criteria for CT with other similar testing techniques

◎ **Popular tools**

- ❖ HAYST method
- ❖ PictMaster

◎ About

- ❖ Orthogonal array based testing technique
- ❖ Developed by Fuji Xerox in 2000
- ❖ "Introduction to the HAYST method" in 2007



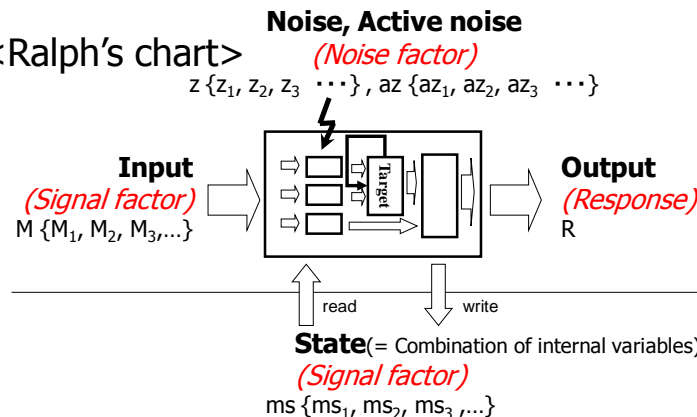
◎ Test case design methodology

- ❖ "Function Verification table" for test analysis
- ❖ "Ralph's chart" for modeling the system under test
- ❖ "Function Level table" for extracting factors and levels

<FV table>

No.	Objective function	Verification contents	Testing technique

<Ralph's chart>



<FL table>

No.	Factor	Level 1	Level 2	...	Level N

⊙ **HAYST method tool “MatrixTester”**

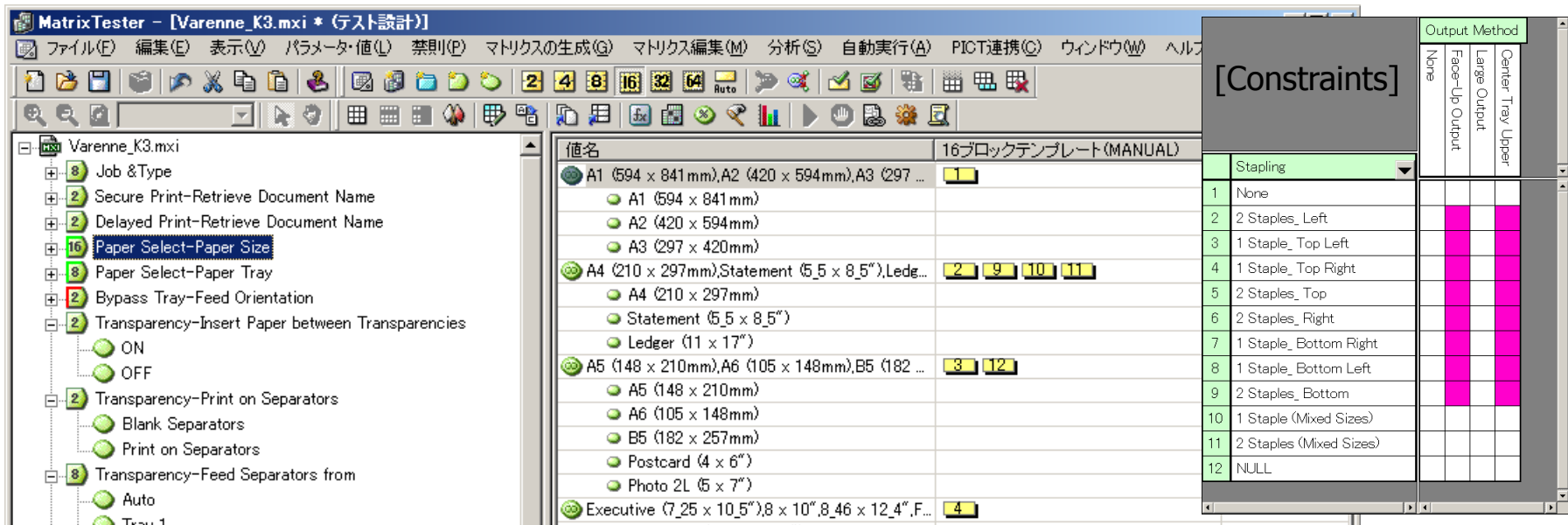
- ❖ Transform from OA (strength 2) templates $L_4 - L_{256}$
- ❖ Constraints handling
- ❖ Partial combination assurance (3, 4, 5 way)
- ❖ Combinatorial coverage calculation

⊙ **Applications**

- ❖ MatrixTester
 - 560 licenses (in-house) and 23 companies (160 licenses)
 - Manufacturers (Automobile, Medical), Financials, Retailing, Consumer Electronics, Communications Equipment, Chemicals
- ❖ Introductory book
 - 4000 copies

(Source: Koichi Akiyama, Fuji Xerox)

◎ MatrixTester : input (factors, levels, constraints)



The screenshot shows the MatrixTester application window. The left pane displays a project tree for 'Varenne_K3.mxi'. The central pane shows a table of factors and levels. The right pane shows a constraints panel with a table of constraints and an output method selection.

値名	16ブロックテンプレート (MANUAL)
A1 (594 x 841mm), A2 (420 x 594mm), A3 (297 ...	1
<ul style="list-style-type: none"> A1 (594 x 841mm) A2 (420 x 594mm) A3 (297 x 420mm) 	
A4 (210 x 297mm), Statement (5.5 x 8.5"), Ledger...	2 9 10 11
<ul style="list-style-type: none"> A4 (210 x 297mm) Statement (5.5 x 8.5") Ledger (11 x 17") 	
A5 (148 x 210mm), A6 (105 x 148mm), B5 (182 ...	3 12
<ul style="list-style-type: none"> A5 (148 x 210mm) A6 (105 x 148mm) B5 (182 x 257mm) Postcard (4 x 6") Photo 2L (5 x 7") 	
Executive (7.25 x 10.5"), 8 x 10", 8.46 x 12.4", F...	4

[Constraints]		Output Method	
		None	Face-Up Output
Stapling			Center Tray Upper
1 None			
2 2 Staples_ Left			
3 1 Staple_ Top Left			
4 1 Staple_ Top Right			
5 2 Staples_ Top			
6 2 Staples_ Right			
7 1 Staple_ Bottom Right			
8 1 Staple_ Bottom Left			
9 2 Staples_ Bottom			
10 1 Staple (Mixed Sizes)			
11 2 Staples (Mixed Sizes)			
12 NULL			

Input type	Explanation
Factor (Parameter)	Name of parameter to be combined
Level (Value)	List of values existing in parameter
Importance of factor	Factors are grouped and it is possible to specify strength for group
Importance of level	Importance of level (Weighting)
Constraint information	Constraint condition in combination between levels
Assignment method	Normal assignment, Partial combination assurance, rating assurance, Level consolidation, Room technique, Strength 3, PICT calling
Detection bug information	Type of bug
Specific factor	Value generation type, Fixed value, Sequence number
Form style	Form style at the time of Excel output
Auto execution support information	Windows Dialog GUI information for auto execution

(Source: Koichi Akiyama, Fuji Xerox)

MatrixTester : output (Test matrix)

MatrixTester - [Varenne_K3.mxi * (マトリクス編集 - マトリクスビュー[128/128])]			
ファイル(F) 編集(E) 表示(V) パラメータ・値(L) 禁則(P) マトリクスの生成(G) マトリクス編集(M) 分析(S) 自動実行(A) PICT連携(C) ウィンドウ(W) ヘルプ(H)			
24 %			
1/2 Page 100 項目 /Page HAYST生成			
No.	自動実行	テスト結...	メモ
1	-	-	
2	-	-	
3	-	-	
4	-	-	
5	-	-	
6	-	-	
7	-	-	
8	-	-	
9	-	-	
10	-	-	
11	-	-	
12	-	-	
13	-	-	
14	-	-	
15	-	-	
16	-	-	
17	-	-	
18	-	-	
19	-	-	
20	-	-	
21	-	-	
22	-	-	
23	-	-	
24	-	-	
25	-	-	
26	-	-	
27	-	-	
28	-	-	
29	-	-	
Job &Type	Secure Print-Retrieve Document Name	Delayed Print-Retrieve Document Name	Paper Select-Paper Size
Normal Print	Enter Document Name	Enter Document Name	A1 (594 x 841mm)
Secure Print	Enter Document Name	Enter Document Name	A2 (420 x 594mm)
Sample Print	Enter Document Name	Auto Retrieve	A3 (297 x 420mm)
Delayed Print	Enter Document Name	Auto Retrieve	A1 (594 x 841mm)
Save to Mail...	Auto Retrieve	Enter Document Name	A2 (420 x 594mm)
Normal Print	Auto Retrieve	Enter Document Name	A3 (297 x 420mm)
Secure Print	Auto Retrieve	Auto Retrieve	A1 (594 x 841mm)
Sample Print	Auto Retrieve	Auto Retrieve	A2 (420 x 594mm)
Normal Print	Auto Retrieve	Enter Document Name	A4 (210 x 297mm)
Secure Print	Auto Retrieve	Enter Document Name	Statement (5.5 x 8.5")
Sample Print	Auto Retrieve	Auto Retrieve	Ledger (11 x 17")
Delayed Print	Auto Retrieve	Auto Retrieve	A4 (210 x 297mm)
Save to Mail...	Enter Document Name	Enter Document Name	Statement (5.5 x 8.5")
Normal Print	Enter Document Name	Enter Document Name	Ledger (11 x 17")
Secure Print	Enter Document Name	Auto Retrieve	A4 (210 x 297mm)
Sample Print	Enter Document Name	Auto Retrieve	Statement (5.5 x 8.5")
Normal Print	Auto Retrieve	Enter Document Name	A5 (148 x 210mm)
Type of output	Explanation		
Test matrix	Result of assignment to orthogonal array		
Test script	Orthogonal array is output to Excel in script format in each line		
Appearance status	Appearance frequency and combination that does not appear		
Rating	Rating of combination between 2 factors and 3 factors		
Round Robin table	Round Robin table indicating appearance status of level combination between 2 factors and 3 factors		
Constraint graph	Graph indicating hierarchical status of constraint and that data table		
Test analysis result	Result of analysis of existence position of bug based on the test result		

⦿ About

- ❖ Pairwise testing tool with Excel based GUI
- ❖ Calls PICT as a test case generation engine
- ❖ Developed by Toshiro Tsurumaki of Iwatsu in 2008

⦿ Applications

- ❖ 20,000 downloads (total) from 2008
- ❖ System testing for Business phone system in IWATSU
- ❖ Automotive OS testing
- ❖ Large scale package software testing

⦿ Download at

<http://en.sourceforge.jp/projects/pictmaster/releases/>

Mr. Tsurumaki can be contacted at LinkedIn "Combinatorial and Pairwise Testing" group.
<http://www.linkedin.com/groups/Combinatorial-Pairwise-Testing-4243185>

(Source: Toshiro Tsurumaki, IWATSU SYSTEM & SOFTWARE)

Major Features

- ❖ GUI support
- ❖ Constraints table (for generating PICT constraints)
- ❖ Expected results table

Microsoft Excel - PictMaster.xls

Y1

PictMaster v5.6 March 11, 2013

Item number	T01	Item name	Configuration testing	Date	
Sub-item number	009	Sub-item name	OS & Browsers configurations	Creator	

Build Edit Settings

Parameters value hierarchy

OS Windows, MacOSX, Ubuntu

Browser IE, Firefox, Chrome, Opera

FlashPlayer 11_4, 11_3, 11_2, 11_1, 11_0

Sub models

Constraints table

Parameters	Constraint 1	Constraint 2	Constraint 3	Constraint 4	Constraint 5
OS	#Windows	Ubuntu			
Browser	#IE	Firefox, Opera			
FlashPlayer		11_2, 11_1, 11_0			

Expected results table

Result	Parameter 1	Parameter 2	Parameter 3	Parameter 4	Parameter 5

	A	B	C
1	OS	Browser	FlashPlayer
2	Windows	Chrome	11_0
3	Windows	Firefox	11_3
4	MacOSX	Chrome	11_1
5			
17	MacOSX	IE	11_4
18	Windows	Firefox	11_0
19	Windows	IE	11_1
20	Windows	IE	11_3
21	Windows	Chrome	11_2

Concluding remarks

◎ **Lessons learned from the history of CT**

For evolution of software testing technology, it needs

- ❖ Openness and collaboration
- ❖ Tools and methodologies

◎ **Challenges in Japan**

- ❖ More focus on upper phase of test process
 - Test architecture design, input modeling
- ❖ Guidelines for choosing the right technique from among many testing techniques
 - For what type of software should CT be applied?